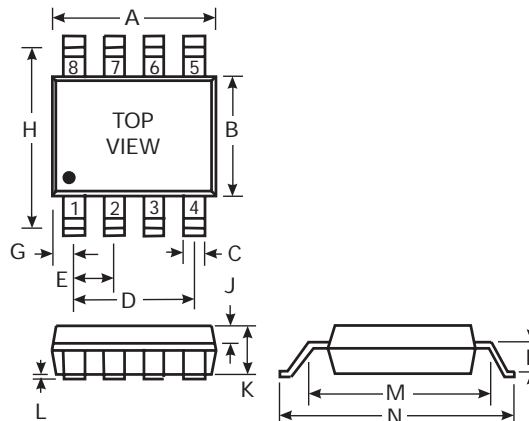
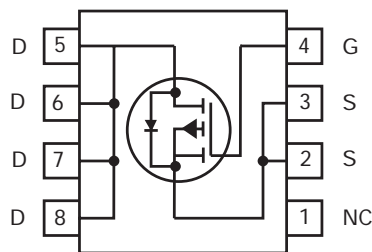


## SINGLE P-CHANNEL ENHANCEMENT MODE FIELD EFFECT TRANSISTOR

### Features

- High Cell Density DMOS Technology
- Low On-State Resistance
- High Power and Current Capability
- Fast Switching Speed
- High Transient Tolerance



SO-8		
Dim	Min	Max
A	3.94	4.19
B	3.20	3.40
C	0.381	0.495
D	2.67	3.05
E	0.89	1.02
G	0.527	0.679
J	0.41 Nominal	
K	0.94	1.09
L	0.025	0.152
M	4.37	4.62
N	4.39	4.70
P	0.939 Nominal	
All Dimensions in mm		

### Mechanical Data

- SO-8 Plastic Case
- Terminal Connections: See Outline Drawing and Internal Circuit Diagram above

### Maximum Ratings @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS}$	-20	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current	$I_D$	$\pm 4.3$ $\pm 3.3$ $\pm 20$	A
Maximum Power Dissipation	$P_d$	2.5 1.2 1.0	W
Operating and Storage Temperature Range	$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$

### Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	50	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	25	$^\circ\text{C/W}$

Notes: 1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance ( $R_{\theta JC} + R_{\theta CA}$ ) where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  in this instance is  $25^\circ\text{C/W}$  but is dependent on the specific circuit board thermal design.

1a. With  $1\text{ in}^2$  of 2 oz. copper mounting pad  $R_{\theta JA} = 50^\circ\text{C/W}$ .

1b. With  $0.04\text{ in}^2$  of 2 oz. copper mounting pad  $R_{\theta JA} = 105^\circ\text{C/W}$ .

1c. With  $0.006\text{ in}^2$  of 2 oz. copper mounting pad  $R_{\theta JA} = 125^\circ\text{C/W}$ .

# Electrical Characteristics

@ T<sub>A</sub> = 25°C unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-20	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = -25 μA
Zero Gate Voltage Drain Current T <sub>j</sub> = 55°C	I <sub>DSS</sub>	—	—	-2.0 -25	μA	V <sub>DS</sub> = -16V, V <sub>GS</sub> = 0V
Gate-Body Leakage, Forward	I <sub>GSSF</sub>	—	—	100	nA	V <sub>GS</sub> = 20V, V <sub>DS</sub> = 0V
Gate-Body Leakage, Reverse	I <sub>GSSR</sub>	—	—	-100	nA	V <sub>GS</sub> = -20V, V <sub>DS</sub> = 0V
<b>ON CHARACTERISTICS (Note 2)</b>						
Gate Threshold Voltage T <sub>j</sub> = 125°C	V <sub>GS(th)</sub>	-0.5 -0.85	-1.65 —	-3.0 -2.6	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250μA
Static Drain-Source On-Resistance T <sub>j</sub> = 125°C T <sub>j</sub> = 125°C	R <sub>DS(ON)</sub>	—	0.053 0.075 0.080 0.120	0.10 0.15 0.16 0.24	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -2.0A V <sub>GS</sub> = -10V, I <sub>D</sub> = -2.0A V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -2.0A V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -2.0A
On-State Drain Current	I <sub>D(ON)</sub>	-2.0 -5.0	—	—	A	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -5.0V V <sub>GS</sub> = -4.5V, V <sub>DS</sub> = -5.0V
Forward Transconductance	g <sub>FS</sub>	—	9.0	—	∅	V <sub>DS</sub> = -15V, I <sub>D</sub> = -4.3A
<b>DYNAMIC CHARACTERISTICS</b>						
Input Capacitance	C <sub>ISS</sub>	—	1425	—	pF	V <sub>DS</sub> = -10V, V <sub>GS</sub> = 0V f = 1.0MHz
Output Capacitance	C <sub>OSS</sub>	—	850	—	pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>	—	430	—	pF	
<b>SWITCHING CHARACTERISTICS (Note 2)</b>						
Turn-On Delay Time	t <sub>D(ON)</sub>	—	17	30	ns	V <sub>DD</sub> = -10V, I <sub>D</sub> = -1.0A V <sub>GEN</sub> = -10V, R <sub>GEN</sub> = 6.0Ω
Turn-On Rise Time	t <sub>r</sub>	—	24	80	ns	
Turn-Off Delay Time	t <sub>D(OFF)</sub>	—	56	200	ns	
Turn-Off Fall Time	t <sub>f</sub>	—	30	200	ns	
Total Gate Charge	Q <sub>g</sub>	—	—	40	nC	V <sub>DS</sub> = -10V, I <sub>D</sub> = -4.3A. V <sub>GS</sub> = -10V
Gate-Source Charge	Q <sub>gs</sub>	—	—	5.0	nC	
Gate-Drain Charge	Q <sub>gd</sub>	—	—	25	nC	
<b>DRAIN-SOURCE DIODE CHARACTERISTICS AND MAXIMUM RATINGS</b>						
Max Continuous Drain-Source Diode Forward Current	I <sub>S</sub>	—	—	-2.2	A	
Drain-Source Diode Forward Voltage	V <sub>SD</sub>	—	-0.78	-1.6	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = -1.25A (Note 2)
Reverse Recovery Time	t <sub>rr</sub>	—	—	80	ns	V <sub>GS</sub> = 0V, I <sub>F</sub> = -1.25A, dI <sub>F</sub> /dt = 100A/μs

Notes: 2. Pulse Test: Pulse width ≤ 300 μs, duty cycle ≤ 2%.

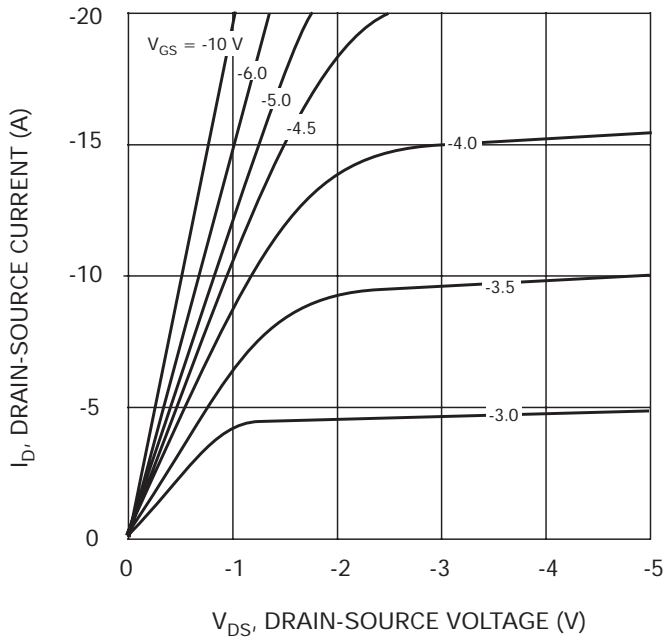


Fig. 1, On-Region Characteristics

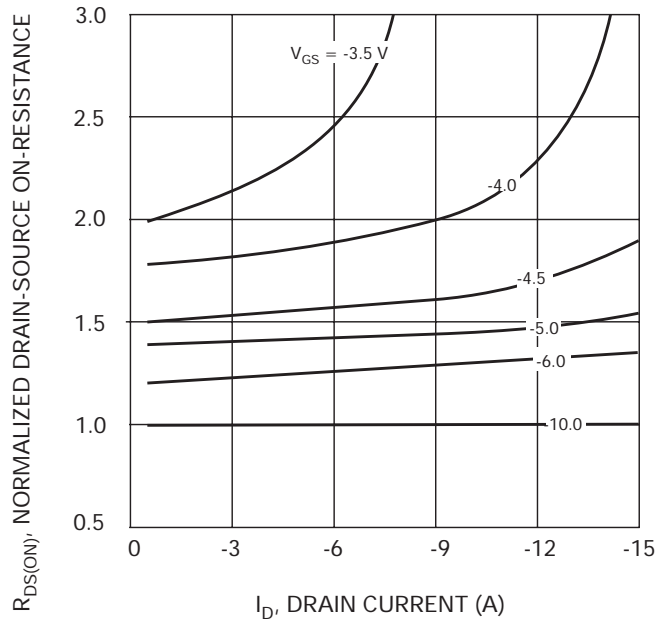


Fig. 2, On-Resistance vs. Gate Voltage & Drain Current

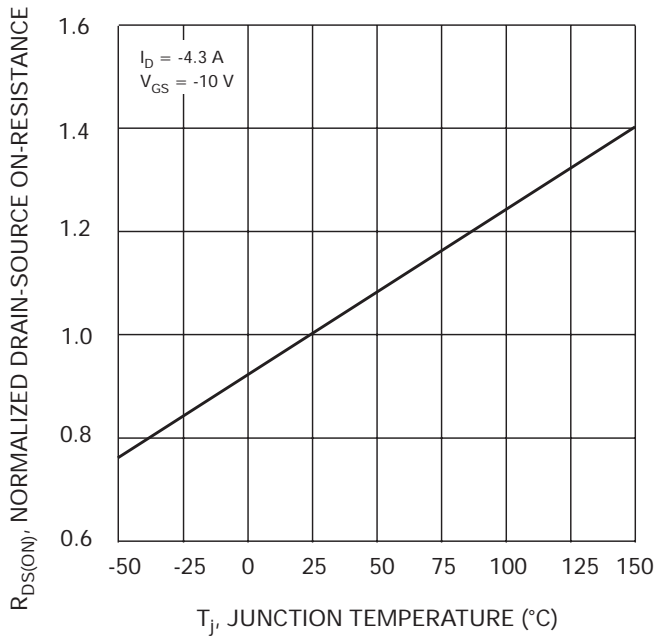


Fig. 3, On-Resistance vs. Junction Temperature

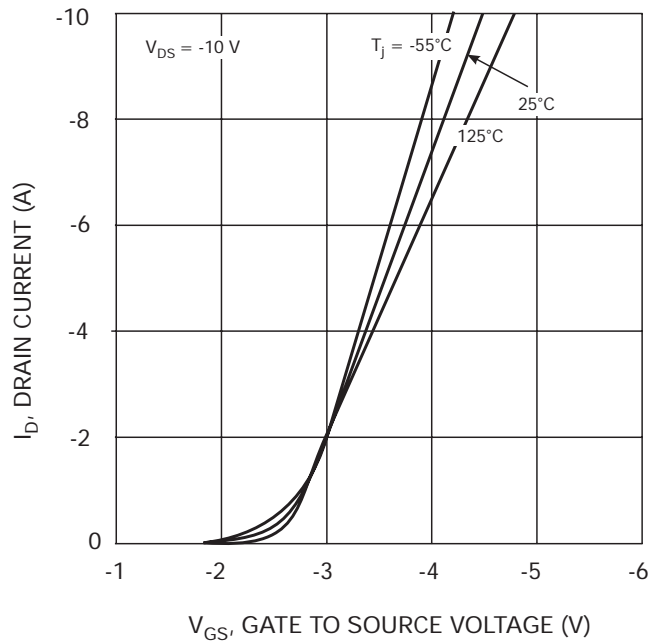


Fig. 4, Transfer Characteristics

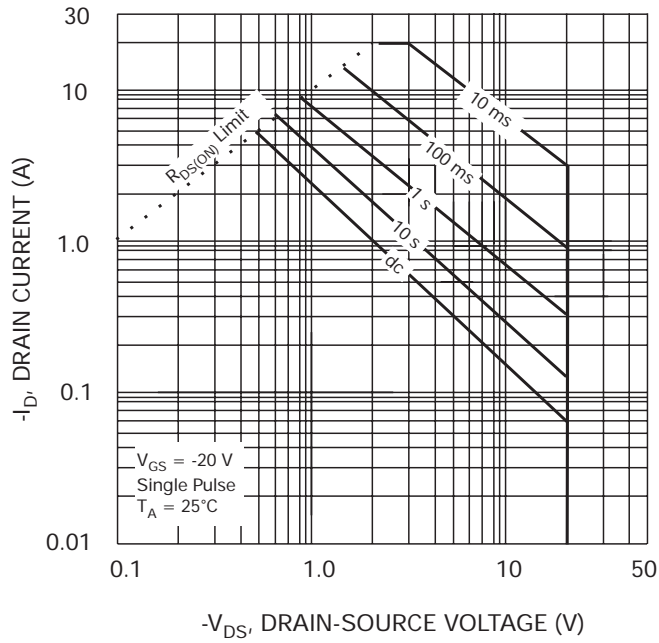


Fig. 5, Maximum Safe Operating Area

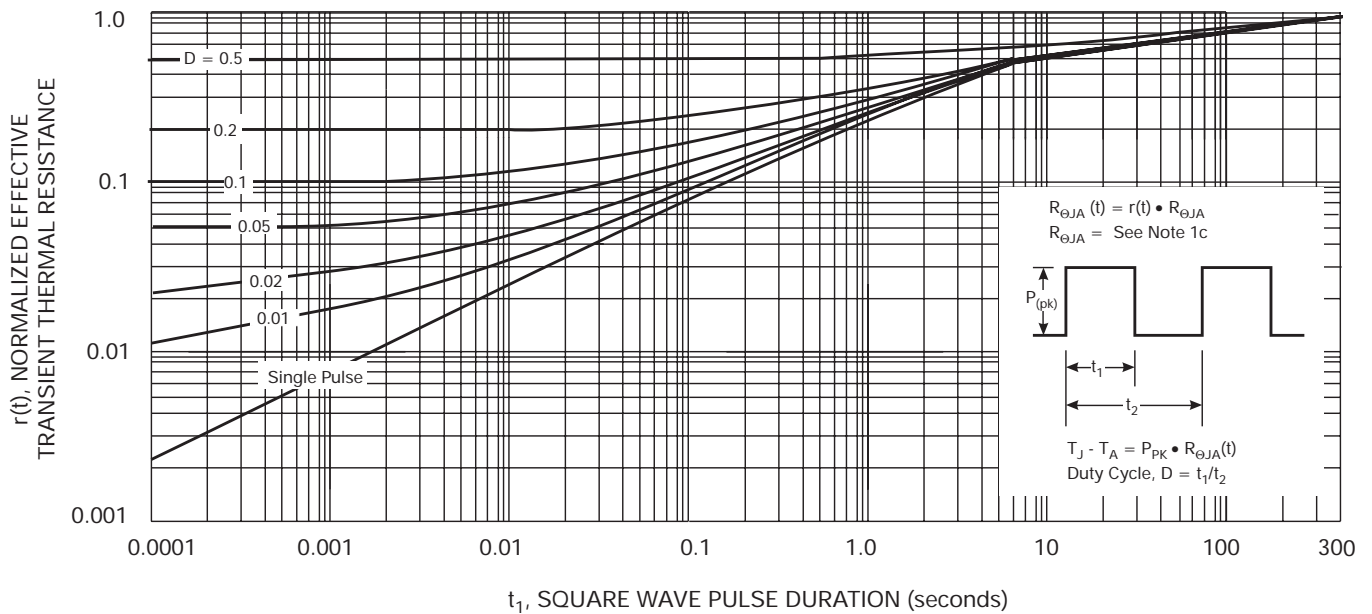


Fig. 6, Typical Normalized Transient Thermal Impedance Curves

Remark: Thermal characterization performed under conditions of Note 1c. Better thermal design such as shown in Notes 1a and 1b or 1d will offer lower  $R_{\theta JA}$  values and allow junction to reach thermal equilibrium sooner.

单击下面可查看定价，库存，交付和生命周期等信息

[>>Diodes Incorporated\(达达科技\(美台\)\)](#)